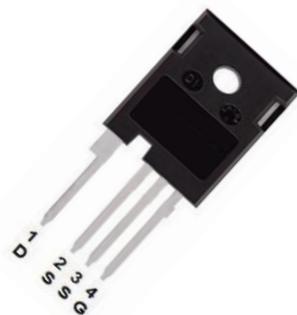


**$V_{DS}$  = 1200 V**  
 **$I_D (T_C=25^\circ C)$  = 59A**  
 **$R_{DS(on).typ} = 40 \text{ m}\Omega @ V_{GS}=20V$**



TO-247-4

## Features

- Wide bandgap SiC MOSFET technology
- Low On-Resistance with High Blocking Voltage
- Low Capacitances with High-Speed switching
- Low reverse recovery(Qrr)
- Halogen free, RoHs compliant

## Benefits

- Reduce switching losses
- Increased system Switching Frequency
- Increased power density
- Reduction of heat sink requirements

## Applications

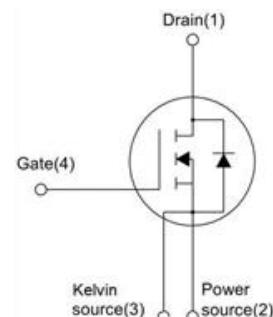
- Switch mode power supplies
- Renewable energy
- Motor drives
- High voltage DC/DC converters

## Package Pin Definitions

- Pin1- Drain
- Pin2- Power Source
- Pin3- Kelvin Source
- Pin4- Gate

## Package Parameters

Part Number	Marking	Package
SMC40N120T4BS	SMC40N120T4BS	TO-247-4



**Maximum Ratings (T<sub>c</sub>=25°C unless otherwise specified)**

Symbol	Parameter	Test conditions	Value	Unit	Note
V <sub>DSmax</sub>	Drain-Source Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 100μA	1200	V	
V <sub>GSm</sub>	Gate-Source voltage	AC (f > 1 Hz)	-10/+25	V	
V <sub>GSo</sub>	Recommend Gate-Source Voltage	Static	-5/+20	V	
I <sub>D</sub>	Continuous Drain current	V <sub>GS</sub> = 20V, T <sub>C</sub> = 25°C	59	A	Fig. 14
		V <sub>GS</sub> = 20V, T <sub>C</sub> = 100°C	42		
I <sub>D,pulse</sub>	Pulsed Drain Current	Pulse with t <sub>p</sub> limited by T <sub>jmax</sub>	160	A	Fig. 18
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25°C, T <sub>j</sub> = 175°C	300	W	Fig. 16
T <sub>j</sub>	Operating junction temperature		-55~150	°C	
T <sub>stg</sub>	Storage temperature		-55~150	°C	
	TO-247 mounting torque	M3 Screw	0.7	Nm	

**Electrical Characteristics T<sub>j</sub>=25°C unless otherwise specified**

**Static Characteristics**

Symbol	Parameter	Test conditions	Value			Unit	Note
			Min.	Typ.	Max.		
V <sub>(BR)DSS</sub>	Drain-Source Breakdown voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 100μA	1200			V	
V <sub>GSt</sub>	Gate Threshold voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 9.5mA		2.6		V	Fig. 9
		V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 9.5mA, T <sub>j</sub> = 175°C		1.5			
I <sub>GSS</sub>	Gate-Source Leakage current	V <sub>GS</sub> = 20V, V <sub>DS</sub> = 0V			250	nA	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 1200V, V <sub>GS</sub> = 0V, T <sub>j</sub> = 25°C		1	100	μA	
R <sub>DS(on)</sub>	Drain-Source On-state Resistance	V <sub>GS</sub> = 20V, I <sub>D</sub> = 40A		42	65	mΩ	Fig. 3, 4, 5
		V <sub>GS</sub> = 20V, I <sub>D</sub> = 40A, T <sub>j</sub> = 175°C		90			
g <sub>fs</sub>	Transconductance	V <sub>GS</sub> = 20V, I <sub>D</sub> = 40A		15		S	Fig. 6
		V <sub>GS</sub> = 20V, I <sub>D</sub> = 40A, T <sub>j</sub> = 175°C		11			

### Thermal Characteristics

Symbol	Parameter	Value			Unit	Note
		Min.	Typ.	Max.		
$R_{th(jc)}$	Thermal resistance from Junction to Case		0.5		K/W	Fig. 15
$R_{th(ja)}$	Thermal resistance from Junction to Ambient		40		K/W	

### Gate Charge Characteristics

Symbol	Parameter	Test conditions	Value			Unit	Note
			Min.	Typ.	Max.		
$Q_{GS}$	Gate to Source Charge	$V_{DS} = 800V$ $I_D = 40A$ $V_{GS} = -5V/20V$		24		nC	Fig. 10
$Q_{GD}$	Gate to Drain Charge			51			
$Q_G$	Total Gate Charge			97			

### AC Characteristics ( $T_J=25^\circ C$ unless otherwise specified)

Symbol	Parameter	Test conditions	Value			Unit	Note
			Min.	Typ.	Max.		
$C_{iss}$	Input Capacitance	$V_{GS} = 0V, V_{DS} = 1000V$ $f = 1 MHz$ $V_{AC} = 25 mV$		2229		pF	Fig. 13
$C_{oss}$	Output Capacitance			110		pF	
$C_{rss}$	Reverse Transfer Capacitance			3.6		pF	
$R_{G(int)}$	Internal Gate Resistance	$f=1 MHz, V_{AC} = 25mV$		1.4		$\Omega$	

Symbol	Parameter	Test conditions	Value			Unit	Note
			Min.	Typ.	Max.		
$t_{d(on)}$	Turn-On Delay Time	$V_{DS} = 800V, V_{GS} = -5V/20V$ $I_D = 40A, R_{G(int)} = 2.2 \Omega$ $L = 100 \mu H$ Inductive load		21.5		nS	Fig. 22
$t_r$	Rise Time			114.5		nS	
$t_{d(off)}$	Turn-Off Delay Time			42.5		nS	
$t_f$	Fall Time			21.5		nS	
$E_{on}$	Turn-On Energy			3.3		mJ	Fig. 21
$E_{off}$	Turn-Off Energy			2.5		mJ	

#### Reverse Diode Characteristics ( $T_j=25^\circ C$ unless otherwise specified)

Symbol	Parameter	Test conditions	Value			Unit	Note
			Min.	Typ.	Max.		
$V_{SD}$	Diode Forward Voltage	$V_{GS} = -4V, I_{SD} = 20A$		4.0		V	Fig. 7, 8
		$V_{GS} = -4V, I_{SD} = 20A, T_j = 175^\circ C$		3.5			
$I_s$	Continuous Forward Current	Diode $T_c = 25^\circ C$		65		A	
$I_{s, pulse}$	Diode Pulse Current	$V_{GS} = -4V$ Pulse width $t_p$ limited by $T_{jmax}$		160		A	
$t_{rr}$	Reverse Recovery Time	$V_{GS} = -4V, I_{SD} = 40A, T_j = 25^\circ C$ $VR = 800V$ $dif/dt = 1000 A/us$		90		nS	
$Q_{rr}$	Reverse Recovery Charge			432		nC	
$I_{rrm}$	Peak Reverse Recovery Current			30		A	

### Typical Performance

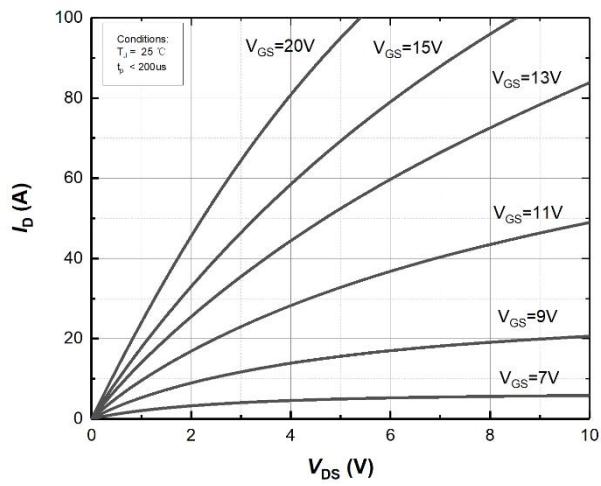


Figure 1. Output characteristics at  $T_j=25^\circ\text{C}$

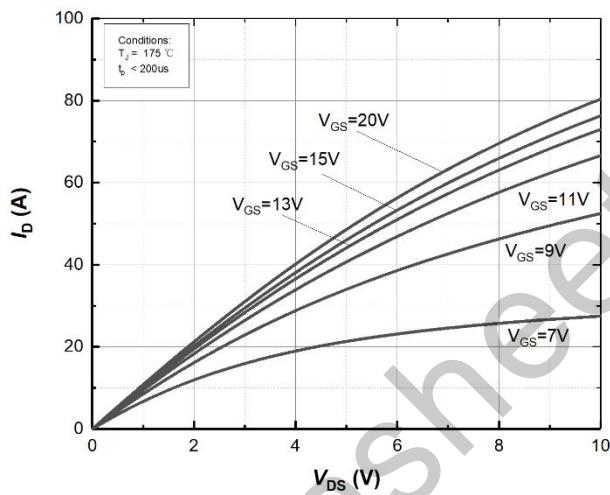


Figure 2. Output characteristics at  $T_j=175^\circ\text{C}$

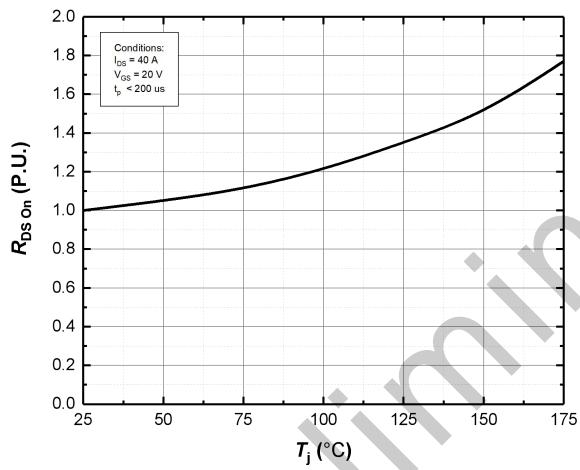


Figure 3. Normalized On-Resistance vs. Temperature

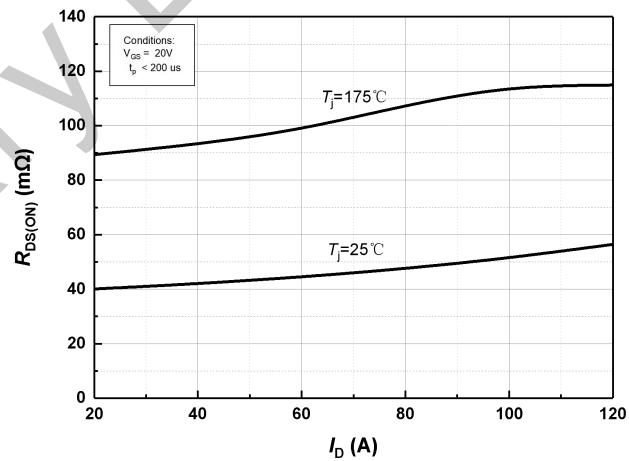


Figure 4. On-Resistance vs. Drain current for Various Temperature

### Typical Performance

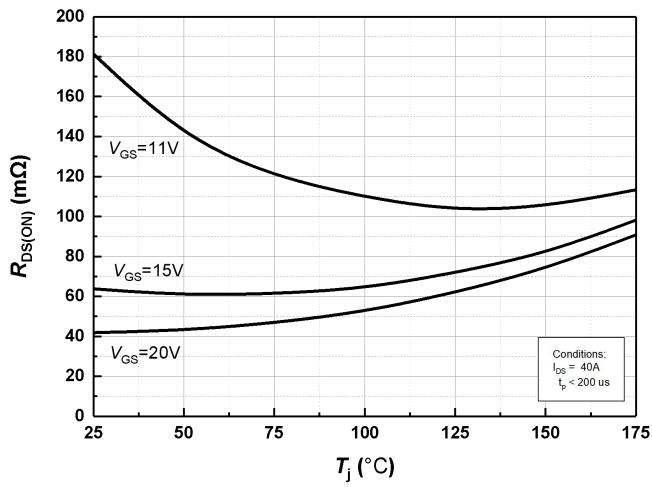


Figure 5. On-Resistance vs. Temperature for Various Gate Voltage

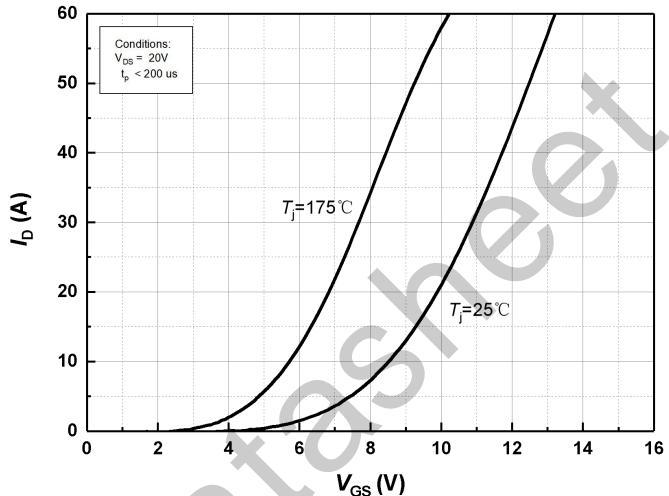


Figure 6. Transfer Characteristics for Various Junction Temperatures

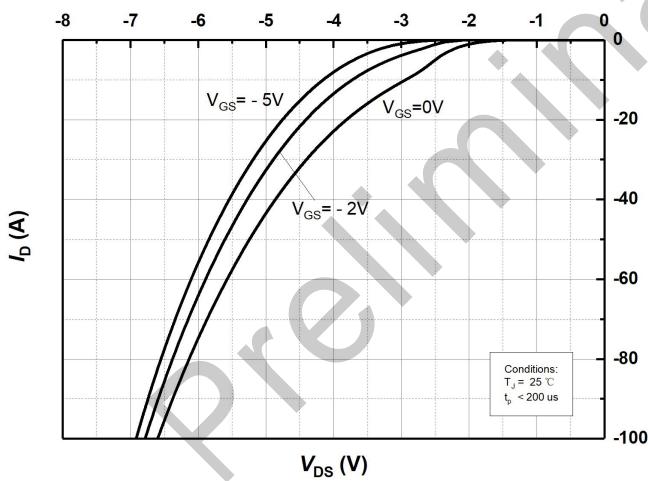


Figure 7. Body Diode Characteristics at  $T_j=25^\circ\text{C}$

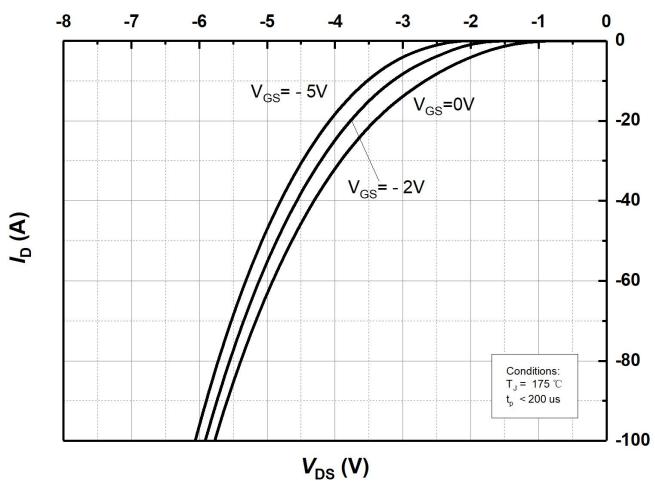


Figure 8. Body Diode Characteristics at  $T_j=175^\circ\text{C}$

### Typical Performance

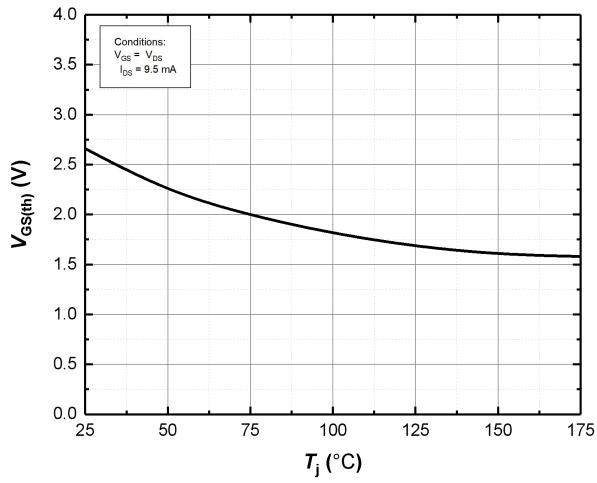


Figure 9. Threshold Voltage vs. Temperature

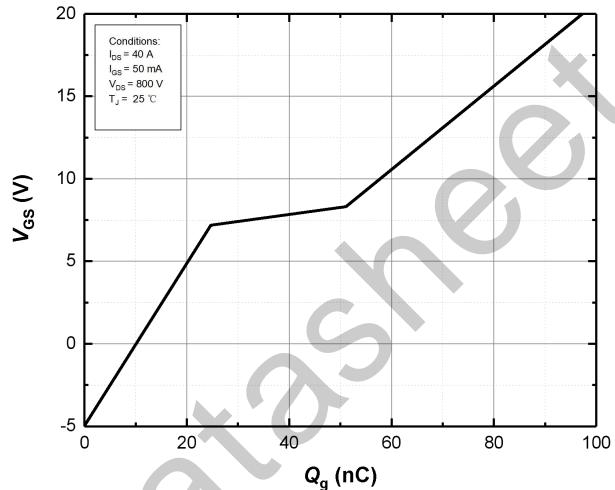


Figure 10 Gate Charge Characteristics

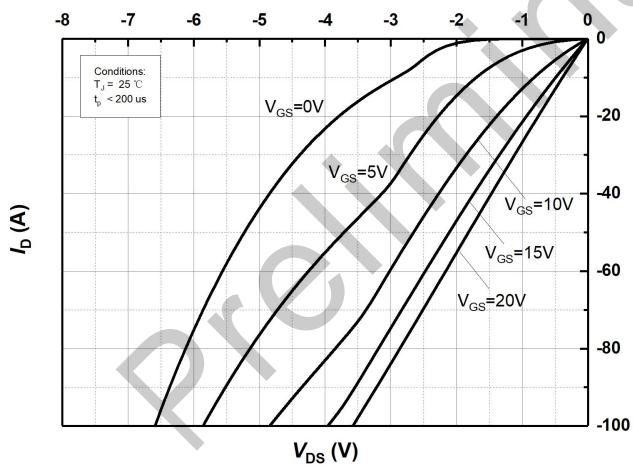


Figure 11. 3rd Quadrant Characteristic at  $T_j=25^\circ\text{C}$

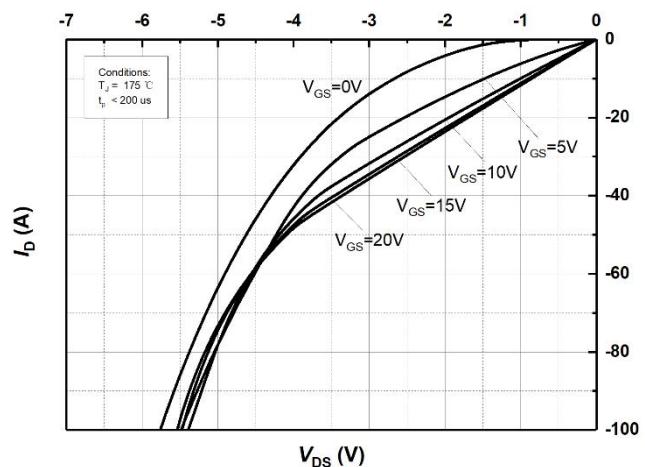


Figure 12. 3rd Quadrant Characteristic at  $T_j=175^\circ\text{C}$

### Typical Performance

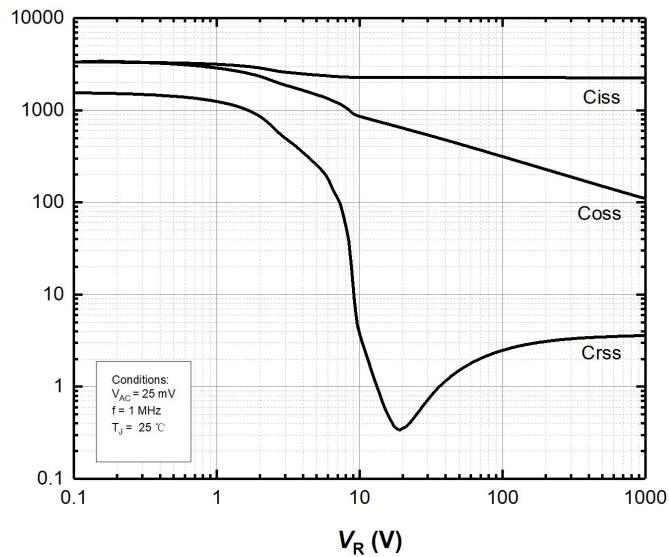


Figure 13. Capacitances vs. Drain-Source Voltage (0 – 1000V)

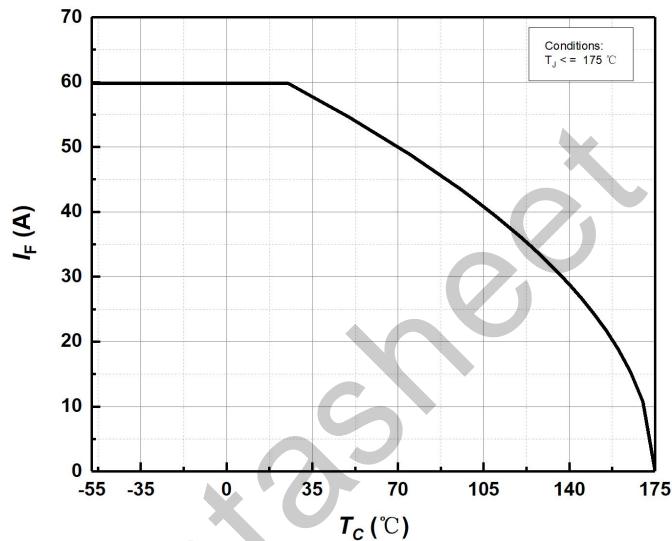


Figure 14. Continuous Drain Current Derating vs Case Temperature

Preliminary Datasheet

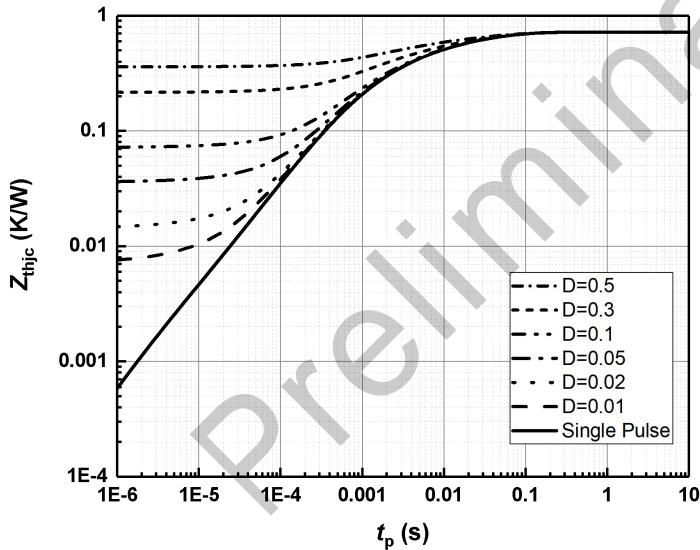


Figure 15. Transient Thermal Impedance (Junction – Case)

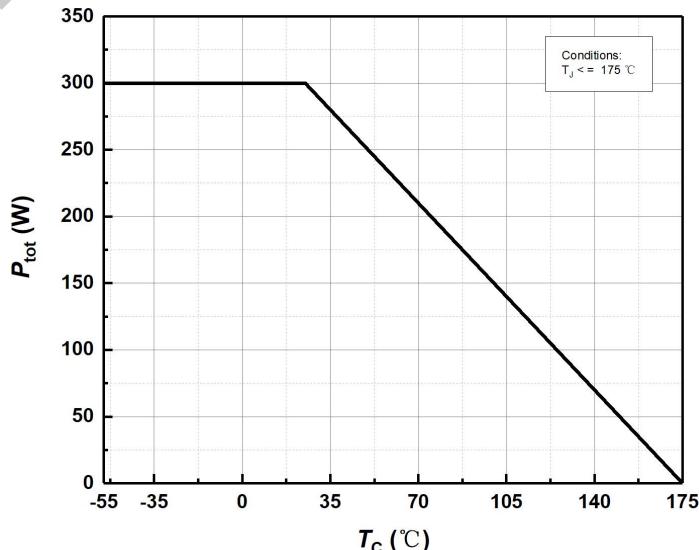


Figure 16. Maximum Power Dissipation Derating vs. Case Temperature

### Typical Performance

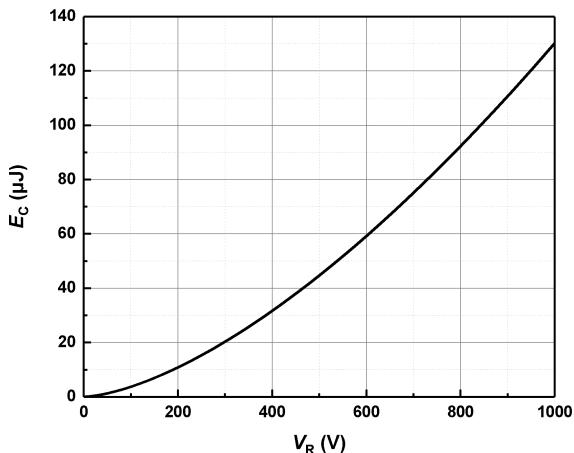


Figure 17. Output Capacitor Stored Energy

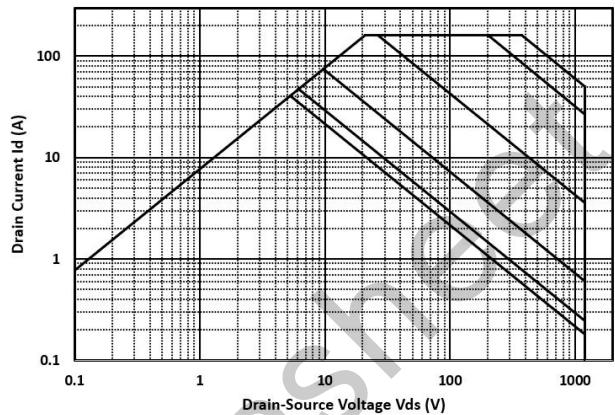


Figure 18. Safe Operating Area

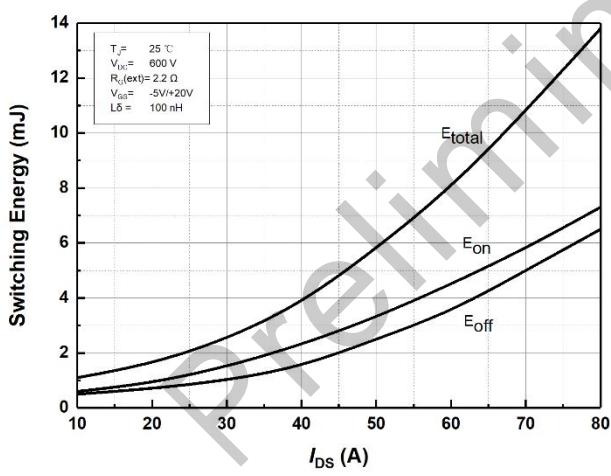


Figure 19. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 600V$ )

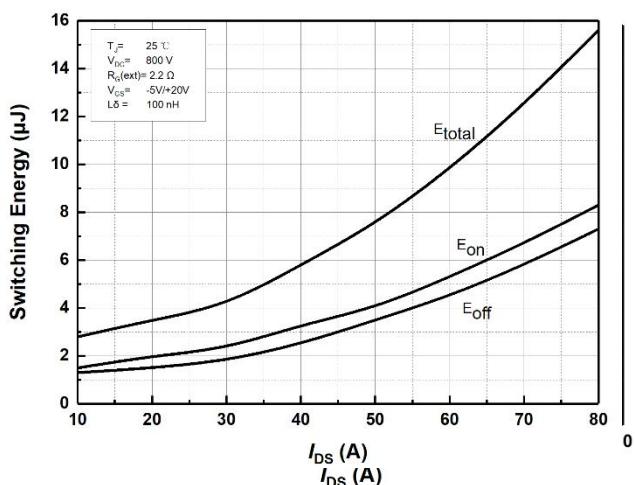
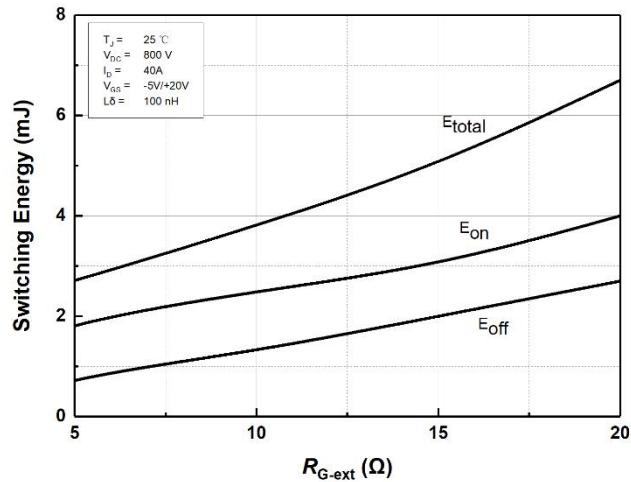
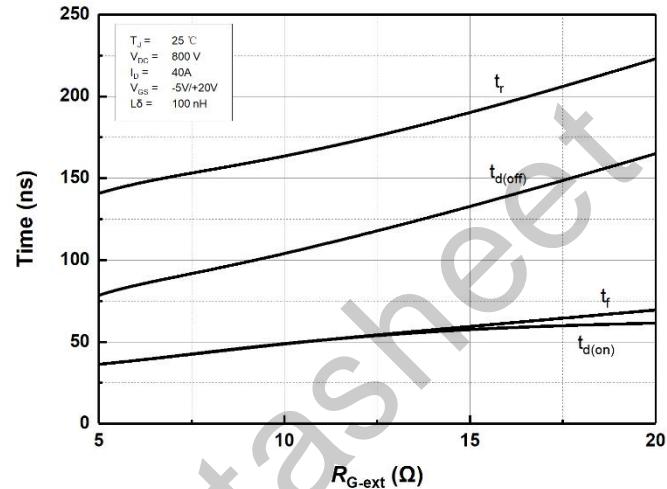


Figure 20. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 800V$ )

### Typical Performance

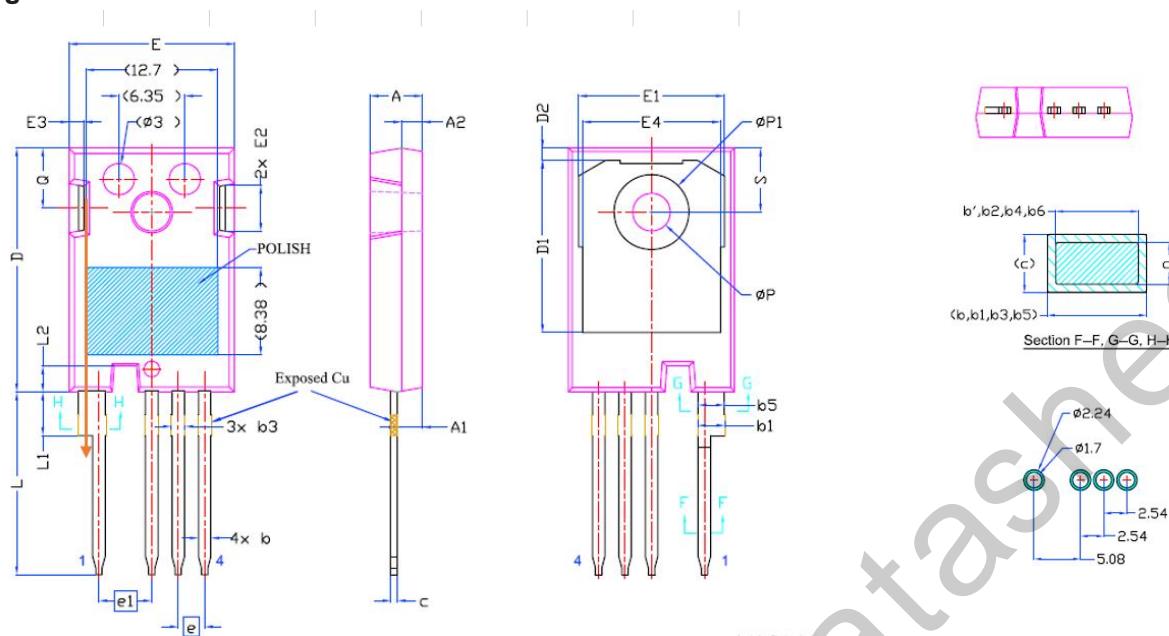


**Figure 21. Clamped Inductive Switching Energy vs.  $R_{G(\text{ext})}$**



**Figure 22. Switching Times vs.  $R_{G(\text{ext})}$**

### Package Dimensions



SYMBOL	MM		
	MIN	NOM	MAX
A	4.80	5.00	5.20
A1	2.21	2.41	2.59
A2	1.85	2.00	2.15
b	1.11	1.21	1.36
b2	1.91	2.01	2.21
b4	2.91	3.01	3.21
c	0.51	0.61	0.75
D	20.70	21.00	21.30
D1	16.25	16.55	16.85
E	15.50	15.80	16.10
E1	13.00	13.30	13.60
E2	4.80	5.00	5.20
E3	2.30	2.50	2.70
e	5.44BSC		
L	19.62	19.92	20.22
L1	NA	NA	4.30
ΦP	3.40	3.60	3.80
ΦP1	NA	NA	7.30
S	6.15BSC		

**Revision History**

Document Version	Date of Release	Description of Changes
Rev 0.0	2022-11-03	Target of the datasheet.

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**Shenzhen, China**  
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